



INFORMATION CITED BY APPLICANT(S) THAT MAY BE MATERIAL TO THE PROSECUTION OF THE SUBJECT APPLICATION

Applicant: T.-Y. Chang et al. Attorney Docket No. SIPT121256
Application No.: 10/601,709 Group Art Unit: ---
Filed: June 19, 2003 Examiner: ---
Title: INTEGRATED CIRCUIT DEVICE WITH A BUILT-IN DETECTING
CIRCUIT FOR DETECTING MAXIMUM MEMORY ACCESS TIME OF AN
EMBEDDED MEMORY

U.S. PATENT DOCUMENTS

*Examiner Cite	Kind	Date	
Initials No. Document No.	Code	(mm/dd/yyyy)	Name
<u>CD</u> U1 6,424,583	✓	07/23/2002	Sung et al.

FOREIGN PATENT DOCUMENTS

*Examiner Cite	Kind	Publication Date	Country	English
Initial No. Document No.	Code	(mm/dd/yyyy)		Abstract Translation
				Provided Provided

None.

OTHER INFORMATION

(Including Author, Title, Date, Pertinent Pages, Etc.)

*Examiner Cite	
Initial No.	
<u>CD</u> O1	Sung and Wu, <i>A Method of Embedded Memory Access Time Measurement</i> , IEEE, 462-465 (2001)
<u>CD</u> O2	Lee, Hsiao and Chang, <i>An Access Timing Measurement Unit of Embedded Memory</i> , IEEE, 104-109 (2002)

Examiner

Date Considered

SON DINH

5/15/04

*Examiner: Initial if reference considered, whether or not citation is in conformance with M.P.E.P. § 609; draw line through citation if not in conformance and not considered. Include copy of this form with next communication to applicant.

SIL:DDP

LAW OFFICES OF
CHRISTENSEN O'CONNOR JOHNSON KINDNESS^{LLC}
1420 Fifth Avenue
Suite 2800
Seattle, Washington 98101
206.682.8100